

Intelligent sampling for the measurement of structured surfaces

Wang, J., Jiang, X., Blunt, L. A., Leach, R. K. and Scott, P. J. (2012).

Measurement Science and Technology, 23 (8), 085006

Online article access:

DOI: 10.1088/0957-0233/23/8/085006

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info@ultraprecision.org